Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/517,454	BOUNY, JEAN-JACQUES
Examiner	Art Unit
Alan Wong	2817

	SEAR	CHED	
Class	Subclass	Date	Examiner
375	397	4/25/2006 ,	AW
	Updated	9/15/2006	AW
<u>-</u>			
			•

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH (INCLUDING SEAR)
	DATE	EXMR
EAST See Printout	4/28/2006	AW
330/149, 124R 333/26 Text Limited See Printout	4/27/2006	AW
Updated	9/15/2006	AW
<u> </u>		
,		